

Notice of References Cited	Application/Control No. 10/800,849	Applicant(s)/Patent Under Reexamination LUONG, MIKE	
	Examiner Tuan N. Nguyen	Art Unit 3751	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,620,529 A	11-1986	Kurosawa, Tadashi	601/157
*	B	US-5,224,224 A	07-1993	Hintz et al.	4/541.1
*	C	US-5,784,728 A	07-1998	Weddendorf et al.	4/571.1
*	D	US-D454,705 S	03-2002	Long et al.	D6/336
*	E	US-D456,154 S	04-2002	Huynh et al.	D6/336
*	F	US-D455,017 S	04-2002	Tran, Hy Van	D6/336
*	G	US-D457,018 S	05-2002	Park, Jeung Hoon	D6/495
*	H	US-6,598,244 B1	07-2003	Yeh, Kuo Chung	4/622
*	I	US-6,698,039 B1	03-2004	Park, Jung Hoon	4/622
*	J	US-6,732,387 B1	05-2004	Waldron, Mark	4/622
*	K	US-6,829,789 B1	12-2004	Liang, Ching-Yao	4/541.1
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.